

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE							ATTY. DOCKET NO.: 5005.1057		SERIAL NO.: To Be Assigned <i>10/633222</i>			
LIST OF PRIOR ART CITED BY APPLICANT (Use several sheets if necessary)											APPLICANT(S): Ulrich KACZYNSKI			
											FILING DATE: Herewith			
											GROUP: To Be Assigned			
U.S. PATENT DOCUMENTS														
*EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBC LASS	FILING DATE IF APPROPRIATE	
<i>JJ</i>	AA	20	03	00	53	0	3	7	Mar. 20, 2003	Blaesing-Bangert et al.	355	53		
	AB													
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FOREIGN PATENT DOCUMENTS														
		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB-CLAS S	TRANSLATION	
<i>JJ</i>	AL	1	0	1	4	0	1	74	Mar. 13, 2003	Germany	G12B	<i>5/00</i>	YES	NO
	AM													
	AN													
	AO													
	AP													
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)														
<i>JJ</i>	AQ	K.-D. Röth und K. Rinn, "Maskenmetrologie mit der LEICA LMS IPRO für die Halbleiter-Produktion", Leica Mikroskopie und Systeme GmbH, Wetzlar (Translation - see Application Text)												
<i>JJ</i>	AR													
<i>JJ</i>	AS													
EXAMINER	<i>John Jones</i>									DATE CONSIDERED	<i>3/3/2005</i>			
'EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.														